Notice of References Cited

Application/Control No. 09/771,542	Applicant(s)/Patent Under Reexamination OKANO, HIDEO		
Examiner	Art Unit		
Jakieda R Jackson	2655	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,516,135	02-2003	Higuchi et al.	386/112
	В	US-6,118,871	09-2000	Okuyama et al.	380/201
	С	US-6,611,652	08-2003	Iwamoto et al.	386/46
	Ď	ŪS-			
	Е	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	a					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE, The Authoritative Dictionary of IEEE Standards Terms 2000, IEE, 7 th edition
	V	ν
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.